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Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/814,174	CHANG ET AL.	
Examiner	Art Unit	
Sophia S. Chen	2852	

	SEAD	CHED		
	SEARCHED			
Class	Subclass	Date	Examiner	
399	51, 220, 221	11/28/2005	sc	
355	20,69,70	11/28/2005	sc	
358	475, 485	11/28/2005	sc	
358	509	11/28/2005	sc	
above	updated	3/20/2006	sc	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interference P.	e Search sintont	3/20/2006	sc
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
358/474 (text search only - see search history printout)	11/28/2005 (updated oil 3/20/16	sc (SC)
EAST (USPAT, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See search history printout	11/28/2005 (updated on 3/20/06	sc (sc)
EAST (EPO, JPO) - See search history printout	11/28/2005	sc
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